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Sommario/riassunto

Written in an accessible and readable style, the book provides a truly integrated, step-by-step approach to the design and construction of low-temperature measurement apparatus. It presents a practical perspective of heat transfer, materials selection, construction techniques, wiring, thermometry, sample mounting, and electrical contacts, and recent developments in superconductor data analysis and scaling theory. The graphs, clear examples, and seventy appendixdata tables are a treasure trove of practical information.